# NINETEENTH ANNUAL Burn-in & Test Strategies Workshop

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## **Bits 2018**

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#### **Contacting Challenges for 5G**

#### Conclusions

5G RF Contacting Solutions must be integrated with the entire test cell between the tester and handler/prober for production environments. A variety of modular contact technology solutions allow for the solution to be adapted to the unique test requirements.

Below is an example of an OTA contactor solution for an AiP device that addressed poor patch antenna quality achieved when antenna was built into PCB.

